

Toward Correlation of Conductance of RuO₂ Nanowire with Plasmon Energy Shift

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Plasmons[1] in RuO₂ nanowires were investigated by electron energy loss spectroscopy attached to high-resolution transmission electron microscopy. It has been found that the plasmon energy increases in proportion to the inverse of the nanowire width. So far the optical techniques such as the photoluminescence spectra measurement or Raman spectroscopy have been used in the investigation. However these techniques do not have enough sensitivity to explore the properties of an individual nano-scale particles, and thus the obtained spectra were always convoluted with the size distribution of the particles.

Electron energy loss spectroscopy (EELS) attached to field-emission gun transmission electron microscopy (FEG-TEM) have been used to overcome this problem. Since the electron probe can be converged to the nanowire width using the condenser lens system of FEG-TEM, we can get the information from an individual nanowire with this technique. RuO₂ nanowires were prepared by a high vacuum furnace with VLS mechanism, and then characterized by a EDX attached on JEOL 2010F FEG-TEM. TEM images and SAD patterns (Fig. 1(b)) were recorded to check the nanostructure and preferential growth direction of the individual RuO₂ nanowires. Fig. 1(c) is the high-resolution image of the nanowire in (b). Fig. 2 is the plasmon spectra of different size nanowires and Fig. 3 shows the plasmon shift with the nanowire size from 13 to 83 nm. And the plasmon peaks shift from 3 to 8.5 eV. For the nanowires, the peak shifts toward higher energy shows the increase of the volume plasmon energy is proportional to the inverse square of the nanowire size. For the insulator or semiconductor[2], the increase of the plasmon energy ΔE_p is can be described as

$$\frac{\Delta E_p}{E_p} = \frac{2\pi^2 \hbar^2}{m^* E_g} \cdot \frac{1}{d^2}$$
, and it shows the characterization of semiconductor differs from the conductor

character in RuO₂ bulk[3]. The electronic property obtained from the scanning tunneling microscopy attached to transmission electron microscopy (STM-TEM) also shows the differ resistance from the bulk and thin film of RuO₂, showed as Table 1.

In summary it has been found by EELS that the plasmon energy in the RuO₂ nanowires increase in proportional to nanowire width and the phenomena can be verified with the electronic properties obtained from STM-TEM.

Reference

- [1] L. Laffont et al., Carbon 40 (2002) 767
- [2] M. Mitome et al., J. Appl. Phys. 72 (2), (1992) 812
- [3] G. Mondio et al., J. Appl. Phys. 82 (4), (1997) 1730

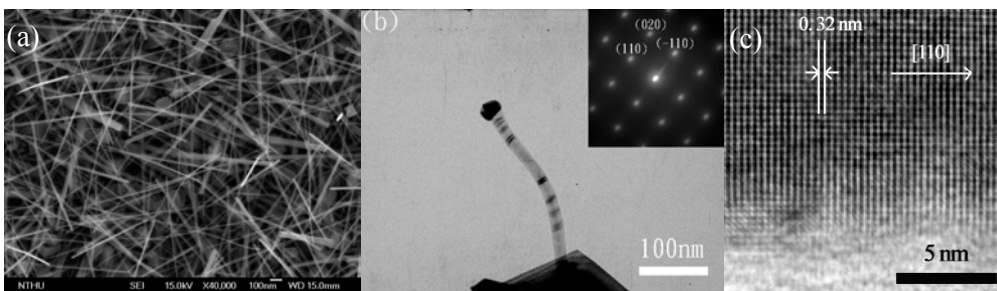


Fig. 1 (a)SEM, (b)TEM and the high-resolution images (c) of RuO₂ nanowire. The black ball on the top of the wire in (b) is the gold catalyst

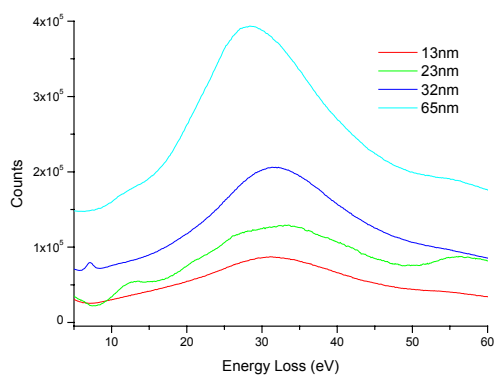


Fig. 2 Plasmon energy shift of different size RuO₂ nanowire

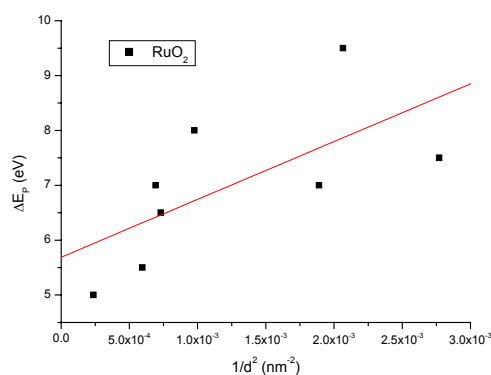


Fig. 3 increase of the plasmon energy with the nanowire size

Table 1 Resistance of different size nanowires obtained from STM-TEM

Nanowire Width (nm)	26.4	28.8	34	42	45	50	75	123	204
Resistance (kΩ)	14.88	13.6	12.27	11.05	26.6	32.6	12.27	27.25	19.7